REMARKS

The claims of the present application have been amended in response to the Examiner's Office Action to place the application in condition for allowance. Applicant has made a concerted effort to present claims which clearly define over the prior art of record, and thus to place this case in condition for allowance.

In the Office Action, the Examiner objected to claims 15 and 21 for not being properly indented. Claims 15 and 21 have been corrected and it is therefore requested that the Examiner's objection be withdrawn.

In the Office Action, the Examiner also rejected claims 15 and 21 as being indefinite; rejected claims 15, 16, 21 and 22 as being anticipated by United States Patent No. 5,841,709 (McClure); and rejected claims 17-20 and 23-26 as being unpatentable over McClure in view of United States Patent No. 6,999,357 (Tanishima). Applicant has amended each of the independent claims to further distinguish the present invention from that which is disclosed in the prior art of record.

Specifically, claim 15 has been amended such that it now specifically claims testing functional memory, repairing the functional memory by adding access to redundant elements, re-testing the functional memory which has been repaired, adding access to additional redundant memory which is not required for the repair, and after re-testing the functional memory and adding access to the additional redundant memory which has been added which was not required for the repair, testing the additional redundant memory which has been added which was not

required for the repair. Claim 21 has been similarly amended but is directed to a mode for testing memory.

Applicant submits that what is now being claimed in claims 15 and 21 is neither disclosed nor suggested by the cited references. For example, in McClure, the memory is tested and a redundant row is mapped to the address of a defective matrix row. Subsequently, during a read or write cycle, when a redundant column has not been mapped to replace a defective matrix column, a selectively conductive element 54 of an enable circuit 44 is made conductive. Inactive pass gates 65 prevent all of the signals from propagating to the node N2 (see col. 7, lines 8-10). McClure does not disclose or suggest testing functional memory, repairing the functional memory by adding access to redundant elements, re-testing the functional memory which has been repaired, adding access to additional redundant memory which is not required for the repair, and after re-testing the functional memory and adding access to the additional redundant memory which has been added which was not required for the repair, testing the additional redundant memory which has been added which was not required for the repair.

In contrast, McClure teaches testing all the matrix-memory columns in a first mode (see col. 7, lines 42-45), and then in a second mode "all of the nondefective columns are tested simultaneously, but only the redundant columns that are mapped to replace defective matrix columns are tested along with the nondefective matrix columns" (col. 8, lines 3-8).
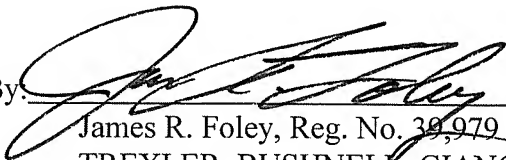
For at least the foregoing reasons, Applicant respectfully submits that claims 15 and 21, and those claims which depend therefrom, are allowable over McClure.

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In view of the above amendments and remarks, Applicant respectfully requests that the present application be passed to issuance.

Should the present claims not be deemed adequate to effectively define the patentable subject matter, the Examiner is respectfully urged to call the undersigned attorney of record to discuss the claims in an effort to reach an agreement toward allowance of the present application.

Respectfully submitted,

Dated: March 20, 2007

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